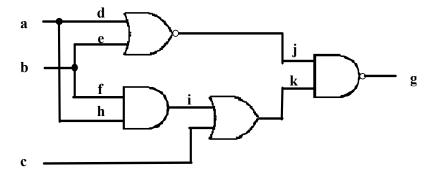
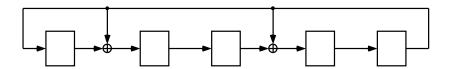
## The University of Alabama in Huntsville ECE Department CPE 628 01 Test 2 November 18, 2008

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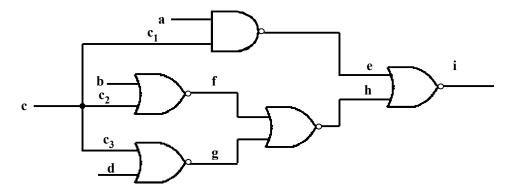
1. (10 points) For the circuit shown, compute all the vectors that can detect h s-a-1 using the Boolean difference.



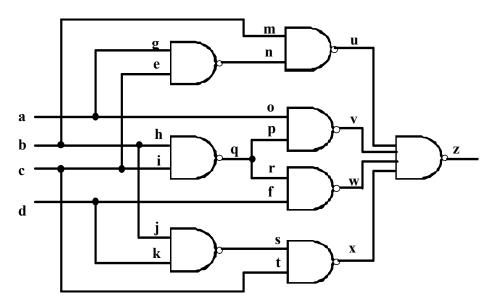

3. (10 points) Consider the following LFSR. Generate the sequence starting with 00001. Is this a maximal LFSR? What is its length?



- 4. (15 points) For the circuit given,
  - a. Compute the static logic implications of c = 0.
  - b. Compute the static logic implications of c = 1.
  - c. Compute the set of faults that are untestable when c = 0.
  - d. Compute the set of faults that are untestable when c = 1.
  - e. Compute the set of untestable faults based on the stem analysis of c.

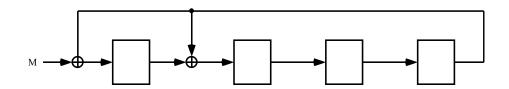


6. (15 points) Using the circuit shown, use PODEM to compute a vector that can detect the fault q s-a-1.



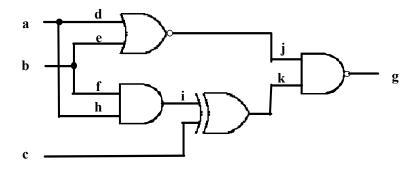
- 7. (1 point) The Logic BIST system most used in industry is named \_\_\_\_\_\_.
- 8. (1 point) An \_\_\_\_\_ fault originates at one clock domain and terminates at the same clock domain.

9. (15 points) Compute the signature of the SISR using f(x) = 1 + x + x4 given for the fault-free sequence  $M = \{110110010101011\}$ . Then, compute the signature for the faulty sequence  $M' = \{111100001100101\}$ . Explain why M' is detected or not detected.



- 10. (1 point) For aligned skewed-load testing a clock \_\_\_\_\_ circuit is used to enable or disable selected shift or capture pulses.
- 11. (1 point) One type of delay fault test is known as a \_\_\_\_\_ delay test.

12. (10 points) For the circuit shown, use the D algorithm to compute a test vector for the fault i s-a1.



13. (15 points) For the circuit shown, insert two test points so the minimum detection probability for any fault in the circuit is greater than or equal to 1/16 and draw the resulting circuit. Assume control points are randomly activated.

